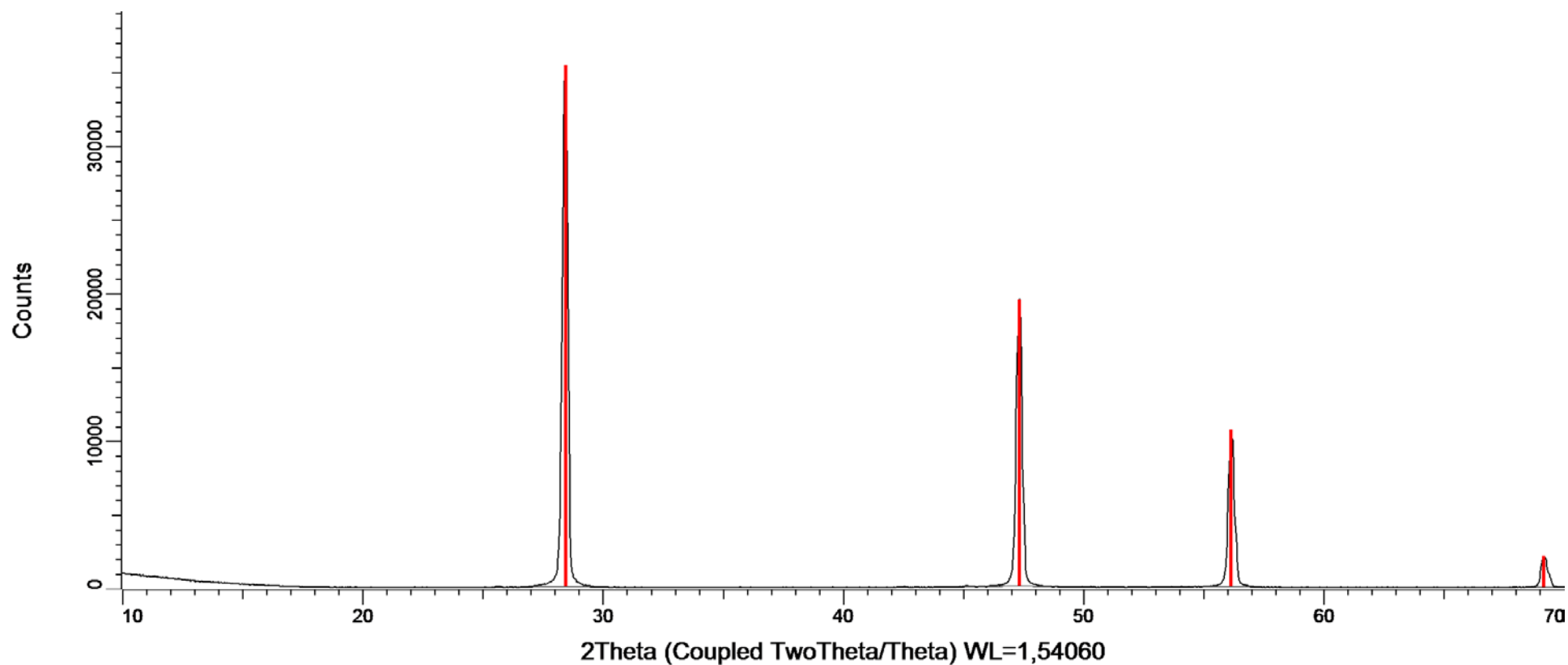


PATRÓN DE SI NIST SRM 640C 23-05-14



- SI NIST TTK450 23-05-14. Barrido tipo Θ - Θ . Rango: 10 a 70 $^{\circ}2\Theta$. Paso: 0,02. Tiempo por paso: 0,2 seg. Cámara: TTK450. Detector: VANTEC.
- Patrón de SI NIST 640c. Cúbico – a 5.43088 - b 5.43088 - c 5.43088 - α 90.000 - β 90.000 - γ 90.000 – Centrado en las caras – Fd-3m (227) – Z 8 – V 160.181

23 de mayo de 2014

INFORME DE CALIBRACIÓN TTK450

Si NIST 640c D8C 23-05-14

Range Number : 1

R-Values

Rexp : 30.26 Rwp : 36.63 Rp : 25.47 GOF : 1.21
Rexp` : 38.42 Rwp` : 46.50 Rp` : 35.61 DW : 1.63

Instrument

Primary radius (mm) 200.5
Secondary radius (mm) 200.5
Linear PSD 2Th angular range (°) 3
FDS angle (°) 0.6
Beam spill, sample length (mm) 14
Intensity not corrected
Full Axial Convolution
Filament length (mm) 12
Sample length (mm) 14
Receiving Slit length (mm) 12
Primary Sollers (°) 2.5
Secondary Sollers (°) 4

hkl Phase - 1 Le Bail method

Phase name Silicio
R-Bragg 1.227
Spacegroup 227
Cell Mass 0.000
Cell Volume (Å³) 159.952(18)
Wt% - Rietveld 0.000
Crystallite Size
Cry size Lorentzian (nm) 194(23)
Cry size Gaussian (nm) 63.8(22)
k: 1 LVol-IB (nm) 44.9(18)
k: 0.89 LVol-FWHM (nm) 47.8(17)

Lattice parameters **NIST 640c Certificate**
a (Å) 5.42829(21) **5.43311946(92)**

h	k	l	m	d	Th2	I
1	1	1	8	3.13403	28.45651	357
0	2	2	12	1.91919	47.32719	627
3	1	1	24	1.63669	56.15211	519
2	2	2	8	1.56701	58.88776	0.275
0	0	4	6	1.35707	69.16845	182

23 de mayo de 2014